

JAGUAR CD ROM DRIVE MODULE

TEST SPECIFICATION

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Section 1	Overview	page 2
Section 2	In-Circuit -Test	page 3
Section 3	Static Burn-in Test	page 5
Section 4	PCBA Functional Test	page 6
Section 6	Diagnostic Test	page 14
Section 7	Test Flowchart	page
Appendix A	PCBA Functional Test	
	Fixture Specification	page 18
Appendix B	Static Burn-in test specification	page 20
Appendix C	Final Systems Test Setup drawing	page

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1.0 Overview

This document describes various test procedure and specifications which must be run in production. It is referred to by various test and QA documents from time to time including the acceptance specification

Section 2 describes the requirements for in-circuit test - the primary tool for identifying and controlling manufacturing costs.

Section 3 describes the requirements for Static Burn-in test

Section 4 describes the requirements for PCBA functional test - designed to check all system functions and provide diagnostic information for systems which do not perform as required.

Section 6 describes the tests that can be used for diagnosis of failed PCBA's.

Section 7 shows the complete test flow chart

Appendix A describes the specification for building the PCBA Functional test fixture

Appendix B describes the Static Burn-in test specification.

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2.0 In - Circuit - Test

2.1 Equipment / Setup

Equipment Required:

The manufacturer is responsible for selecting the equipment, building fixtures and generating the in-circuit test program. The manufacturer must provide Atari with a summary of tests performed on each components, including the level of coverage, tolerances, and a list of components not tested. Additional function tests may be required depending on the level of testing achieved at in-circuit test.

Unit Under Test:

APN 700037 Jaguar CD ROM Drive Printed Circuit Assembly.

Test Condition:

Temperature: 25 degree C +/- 4 degree C

Setup:

Set UUT on ICT fixture and start test,

2.2 Shorts Test

A shorts test must be performed on all nodes accessible to the test fixture. Any node not included in the shorts test must be summarized and reported to Atari.

2.3 Analog Passive Parametric Test

A parametric value test must be performed on all analog passive components

individually accessible. Values and tolerances should match the bill of materials,

Parallel analog passive components should be tested in parallel. Any analog

passive components not tested must be summarized and reported to Atari.

2.4 Active Devices Test

Each input pin on active analog and digital devices must be driven/state toggled while the device is powered and level/state changes received on each device output pin. Any device not 100% tested must be summarized and reported to Atari.

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2.5 Frequency Test

Crystals X1 and X2 must be measured to better than 0.0025%

2.6 Memory Test

A CRC and checksum test of the 8bit ROM must be provided.

2.7 Voltage Test

Verify Supply Voltage at TP337 (Pin 5 of U5) and GND (Pin 3 of U13)
= **5V DC +/-0.050V**

Verify Supply Voltage at TP334 (Pin 5 of U5) and GND (Pin 3 of U13)
= **7V DC +/-0.050V**

Verify Voltage at TP35 (Pin 9 & 10 of U8) and GND (Pin 12 of U8)
= **2.50V DC +/- 5%**

Verify Voltage at TP89 (Pin 14 of U4) and GND (Pin 15 of U4)
= **1.15V DC to 1.31V DC**

Verify Voltage at TP88 (Pin 4 of U3) and GND (Pin 21 of U3)
= **1.35V DC +/- 10%**

Verify Voltage at TP23 (Pin 7 of U1) and GND (Pin 14 & 10 of U1)
= **2.50V DC +/- 5%**

2.8 Custom ASIC's

Custom ASIC's are fully tested at the vendor. The preferred Atari method for checking opens is HP Test Jet on the HP 3070.

2.9 Reports

A variety of weekly reports must be provided:

- a. Overall yield and first pass yield (boards must be serialized),
- b. Failure Pareto charts identifying top 10 failing tests.
- c. Repair Pareto charts identifying top 10 component repairs.

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3.0 Static Burn-in Test

This test is conducted in a burn-in rack, with power applied to PCBA and without exercising any software. This test is conducted on all production unit.

3.1 Equipment / Setup

Equipment Required:

Interconnect PCBA with 5V DC Supply voltage
Power Distribution Network
Burn-in facility
High Capacity Dual Voltage Power Supply (+9VDC, +5VDC)

Unit Under Test:

APN 700037 Jaguar CD ROM Drive Printed Circuit Assembly.

Test Condition:

Temperature : 50 degree C

Setup:

Set UUT in the burn-in rack
Apply 9VDC to UUT power jack.
Apply 5VDC to UUT through interconnect PCBA.
Set burn-in rack temperature to 50 degree C.

Burn-in:
The UUT with 9VDC and 5VDC power applied, will remain in the burn-in rack for a period of 8hrs. At the end of 8hrs, the PCBA functional test is performed on the UUT.

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4.0 PCBA FUNCTIONAL TEST

This test is required on 100% of all production.

4.1 Equipment / setup

Equipment required:

Manufacturer must provide a bed of nails test fixture that contains a Jaguar console containing test software and a known good CD ROM DRIVE (CDM 12) mechanism with an Atari Test CD mounted. The UUT and Jaguar console are powered by Atari AC wall plug adapters. The Jaguar console is connected to an IBM PC serial port with a custom Jaguar serial data cable software running on the Jaguar console starts and stops the mechanism as required by the tests. The test is approximately 2 minutes and 20 seconds long.

Atari CD ROM Test Disc
AC wall plug power adapter (2 required)
Suite 2 Test Software.
Custom Jaguar serial data cable.
IBM PC
Leader LJM 1851 CD Jitter Meter

Unit Under Test:

APN 700037 Jaguar CD ROM DRIVE PCB assembly.

Test Conditions:

Temperature: 25 degree C +/- 4 degree C
Humidity: 25% to 70% relative humidity

Setup:

Set UUT on the test fixture
Connect UUT to Jaguar console PCBA via CD ROM extender card.
Connect CD ROM DRIVE Mechanism to UUT.

Place Atari Test CD on the CD ROM DRIVE Mechanism.
Connect AC adapter to UUT power jack.
Connect AC adapter to Jaguar console PCBA.
Connect Jaguar PCBA to IBM PC serial port via a custom Jaguar
serial data cable..
Power ON to start the test software on the Jaguar Console PCBA.
The terminal displays the message
“Please wait for sanity check to complete”

If the sanity check passes the terminal will display the message
“ Quick check passed. Starting PCBA tests “

The automated test series begins at this point
The automated test series checks the following:
EEPROM write / read back
FFFF/0000 words serial data test
Dual counter serial data test and
Butch FIFO to Tom 32-bit data test.

At the end of a successful test series the terminal displays the message
“ UUT self test passed Congratulations”
“ External evaluation required for the following tests”

At the end of each measurement type any key on the PC to begin the next test.

4.4.5 Block error rate (BLER) at inner and outer diameters of disc

Note: To perform this test, the UUT should have the following modification

- a) The jumper link at JP225 should be between pins 2 and 3.
- b) Pin 2 of JP 210 (BTCH V4) should be pulled high to VCC by a pull up resistor (4.7K 1/4W)

This automated test measures BLER on the inner and outer tracks of the Atari Test Disc, at double speed. As the test proceeds, the message

BLER count was \$xxxx

This message appears 8 times

The test operator has to inspect the BLER count and determine if the PCBA has passed or failed the BLER test.

All BLER counts less than \$0064 ----- PCBA **passed** the BLER test
Any BLER count greater than \$0064 ----- PCBA **failed** the BLER test

4.3 Complete System Voltage and Current Test:

4.3.1 Power Supply current (measured at the supply point)

On the power cord, near the power input jack on the CD ROM PCB,
measure the input current

Should be = **111 mA. +/- 10 mA**

4.3.2 Power Supply current draw after regulator U5 (+5V)

Measured between JP224 Pin 1(TP9) and JP224 Pin 2 (TP337)

Should be between **55 to 65 mA.**

4.3.3 Power Supply current draw after regulator U13 (+7V)

Measured between JP223 Pin 1(TP63) and JP223 Pin 2 (TP334)

Should be between **24 to 30 mA.**

Note that this is the value “C” used below.

4.3.4 Laser Current

Voltage at TP60 (R24), focus off = (your measurement A)

Voltage at TP60 (R24), focus on = (your measurement B)

Calculate current: $I_{\text{laser}} = (B-A) / 4.7$

Verify that $I_{\text{laser}} < 76 \text{ mA.}$

4.3.5 Focus Current

Measure current between JP223 Pin 1(TP63) and JP223 Pin 2 (TP334)

= ‘D’ mA

Calculate current: $I_{\text{focus}} = D - C$

Verify that $I_{\text{focus}} < 50 \text{ mA}$

4.3.6 Spindle motor current at double speed

With the test CD spinning at double speed in the drive, focus and radial off,
measure current between JP223 Pin 1(TP63) and JP223 Pin 2 (TP334)

= ‘F’ mA

Calculate current : $I_{\text{spindle 2}} = F - C$

Verify that $I_{\text{spindle 2}} < 60 \text{ mA}$

4.3.8 Peak Hold current

As the test software starts and stops the drive repeatedly, measure the peak
current between JP223 Pin1(TP63) and JP223 Pin 2(TP334).

Verify that $I_{\text{peak}} < 1000 \text{ mA each time.}$

4.5 Behavior of spindle motor

These tests are performed with the disc spinning at double speed.

4.5.1 Spindle motor DC voltage at inner diameter of disc

Measure the DC voltage between pin 3 (TP362) and pin 4 (TP363) on JP4 (motor cable connector) and verify that...

$$V_{\text{motor DC}} = 1.18 \text{ Volts, +/- 20\%}$$

4.5.2 Spindle motor RMS voltage at inner diameter of disc

Measure the RMS voltage between pin 3 (TP362) and pin 4 (TP363) on JP4 (motor cable connector) and verify that...

$$V_{\text{motor RMS}} = \text{TBD Volts, +/- 20\%}$$

4.5.3 Spindle motor DC voltage at outer diameter of disc

Measure the DC voltage between pin 3 (TP362) and pin 4 (TP363) on JP4 (motor cable connector) and verify that...

$$V_{\text{motor DC}} = 0.66 \text{ Volts, +/- 20\%}$$

4.5.4 Spindle motor DC voltage at outer diameter of disc

Measure the RMS voltage between pin 3 (TP362) and pin 4 (TP363) on JP4 (motor cable connector) and verify that...

$$V_{\text{motor RMS}} = \text{TBD Volts, +/- 20\%}$$

4.4 HF Signal Quality Measurement:

The high frequency RF signal input to the Philips 7345 decoder is measured with a Leader LJM 1851 CD Jitter Meter and Jaguar self test software block error (BLER) counter. Connect Jitter Meter probe to TP34 and ground to TP345 (Pin 1 of JP219) of the UUT.

Turn ON the Jitter Meter. The Jitter Meter setup should be as follows:

LEVEL : Range(V_{pp}) -- 1.5V
Bit ----- 3T Bits
JITTER : Response ----- Sigma
Range ----- 60 nS range
Polarity ----- Inverted

4.4.1 & 4.4.2 I₃ Voltage P-P and Jitter at disc ID

Verify that $I_3 = 1.05$ Volts P-P +/- 20%
Verify that $J_{re} < 32$ nanoseconds

4.4.3 & 4.4.4 I₃ Voltage P-P and Jitter at disc OD

Verify that $I_3 = 1.05$ Volts P-P +/- 20%
Verify that $J_{re} < 32$ nanoseconds

If the complete test series is successful, the terminal will display the message.

“UUT test Complete”

“UUT self test passed, Congratulations”

The terminal then display the following messages

Main Menu

- (B) BLER tests, Needs JP225 and 4.7K resistor**
- (C) Current and voltage tests on PCBA**
- (D) Data integrity tests using Jerry , then Tom**
- (E) EEPROM write and read back test**
- (F) Film clip endless-loop playback**
- (H) Hole-in CD tolerance test, Needs SBC444A CD**
- (J) Jitter tests**
- (R) RW Sub codes for CD + Graphics tests**
- (S) Seeks of decreasing Spans tests**

Waiting.....

The test operator can select any test in the menu by the letter. Test selection from the Main Menu becomes necessary only when the UUT fails the initial test series and the test operator wants to repeat a failed test. The test software in the Jaguar console runs the selected test and the terminal displays the Main Menu enabling the test operator to select any other test in the

menu.

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5.0 Final Systems test

This is an automated functional test series performed on the device under test.

During the test, the TV screens remains blue. If the test ends successfully, the screens turns green. Any failure of the device under test causes the test software (residing in the test cartridge) to make the TV screens turn red and exit the test. The duration of the test series is less than 1.5 minutes.

5.1 Equipment / Setup

Equipment Required:

- Jaguar game console (2 units)
- Suite 1 Test cartridge A
- Suite 1 Test cartridge B
- Suite 1 Test CD ROM
- AC Power Adapter (4 required)
- Jaguar joystick mating connector with
tricolor (red,yellow,green) L.E.D (2 required)
- Jaguar CD ROM Player PCBA (modified for BLER measurment)
in bottom case.

Unit Under Test:

APN 800016-001 Jaguar CD ROM DRIVE Console

Test Conditions:

Temperature: 25 degree C +/- 4 degree C
Humidity: 25% to 70% relative humidity

Setup:

Refer setup diagram for reference.

Mount UUT on Jaguar game console A.

Insert the Suite 1 test Cartridge A into the game cartridge port of the UUT.

Connect the first connector with tricolor L.E.D to joystick port 1 of Jaguar game console A.

Mount Jaguar CD ROM Player PCBA on Jaguar game console B.

Insert the Suite 1 test Cartridge B into the game cartridge port of the CD ROM player PCBA.

Connect the second connector with tricolor L.E.D to joystick port 1 of Jaguar game console B.

Connect AC adapter to power jacks of Jaguar game consoles A and B.

Connect AC adapter to UUT power jack.

Connect AC adapter to CD ROM player PCBA power jack.

Lift CD cover of the UUT, place Suite1 CD ROM test disk and close cover.

Plug BLER signal and ground wires from cartridge A into the BLER measuring terminals on the CD ROM player PCBA (modified for BLER measurement)

mounted on Jaguar console B.

5.2 Test Description:

Power up the Jaguar consoles A and B simultaneously by pressing the red switch on the Jaguar consoles.

Observe the yellow L.E.D flash on Jaguar console A as the test series begins.

Wait for green or red L.E.D to light up on the Jaguar consoles A and B.

If Green L.E.D lights up on Jaguar consoles A and B, it indicate the UUT has

PASSED the test series.

If Red L.E.D lights up on Jaguar consoles A and B, it indicates the UUT has FAILED the test series.

Turn off the UUT power.

Turn off the CD ROM PCBA power.

Turn off power to Jaguar consoles A and B.

Open cover of the UUT and remove CD ROM test disk.

Remove Test Cartridge from UUT.

Remove UUT from Jaguar console.

5.4 Mechanical / Cosmetic Inspection

The following mechanical/cosmetic items inspection shall be done at final test and during the final assembly stages.

- No missing screws
- No loose internal parts
- No unacceptable molding defects in plastic case
- No scratches, dirt, or finger prints on case
- CD ROM drive mechanism properly clamped to PCA
- Correct serialized rating label in place
- Correct Laser Safety label in place
- Correct Class 1 Laser label in place

- PCBA properly aligned in plastic case.
- No bent or warped EMI shields
- EMI Shields properly placed inside the case.
- CD cover shall open without any friction when eject knob is pressed.
- CD cover when opened, shall stand in opened position until closed by the user
- CD shall stop spinning when cd cover is opened.

5.5 Packout Inspection

All items listed on the BOM shall be included as described on the associated assembly drawings. The gift box shall be weighed to check if any item is missing inside the box.

This ends the final system test.

5.6 Report

Failure data shall be collected on all nonconforming units by failure code. Repair actions associated with failure code shall also be collected. This information shall be reported to Atari monthly. In addition, information on top 10 test failures and top 10 repair actions shall be reported weekly to Atari

in Pareto chart format.

5.7 Fully Automated Functional Test Error Messages

<u>Automated Test</u>	<u>Failure Message or State</u>
1. Door open/closed switch	no test start
2. Data Integrity	(type) failed
3. Audio playback	DSA error condition
4. Multiple seek speed test	DSA error condition
5. Verify CIRC detection circuit	no SAA7345 MISC output
6. Subcode R-W channels	Subcode R-W not valid
7. EEPROM read/write	failed
8. Subcode Q	no subcode Q on V4

6.0 Diagnostic Tests

Any test contained in the Final Systems Test can be executed manually as
a diagnostic test, when the UUT is connected to a serial data terminal or PC emulating a serial data terminal. The Static behavior of servo test and the Gain tests are not available as part of the production tests but can be invoked to troubleshoot defective units in diagnostic mode

6.1 Static behavior of servo drivers

These tests are performed with power on the circuit, but no disc in the drive.

6.1.1 Focus driver offset voltage

Measure the voltage between pin 2 (TP366) and pin 3(TP367) on JP3 (flex circuit connector) and verify that...

$$V_{\text{focus 1}} = 0.00 \text{ Volts, } \pm 0.450 \text{ V}$$

6.1.2 Radial driver offset voltage

Measure the voltage between pin 1(TP369) and pin 4(TP368) on JP3(flex circuit

connector) and verify that...

$$V_{\text{radial } 1} = 0.00 \text{ Volts, } +/- 0.450 \text{ V}$$

6.1.3 Sled driver offset voltage

Measure the voltage between pin 5(TP364) and pin 6(TP365) on JP4(motor cable connector) and verify that...

$$V_{\text{sled}} = 0.00 \text{ Volts, } +/- 0.450 \text{ V}$$

6.1.4 Spindle driver offset voltage

Measure the voltage between pin 3(TP362) and pin 4(TP363) on JP4(motor cable connector) and verify that...

$$V_{\text{motor } 1} = 0.00 \text{ Volts, } +/- 0.450 \text{ V}$$

6.2 Gain tests

Note that the following 3 gain tests can damage the circuit if run for more than 5 seconds. The '!!' preceding each test is a reminder of this fact.

6.2.1 !! Focus driver gain

Apply 3 volts to TP86 and measure the voltage between pin 2(TP366) and pin 3 (TP367) on JP3 (flex circuit connector) and verify that....

$$V_{\text{focus } 2} = 0.780 \text{ Volts, } +/- 20\%$$

6.2.2 !! Radial driver gain

Apply 3 volts to TP87 and measure the voltage between pin 1 (TP369) and pin 4 (TP368) on JP3 (flex circuit connector) and verify that....

$$V_{\text{radial } 2} = 0.780 \text{ Volts, } +/- 20\%$$

6.2.3 !! Spindle driver gain

Apply 3 volts to TP84 and 2 volts to TP 85 and then measure the voltage between pin 3(TP362)and pin 4(TP363) on JP4 (motor cable connector) and verify that....

$$V_{\text{motor 2}} = 0.780 \text{ Volts, } +/- 20\%$$

6.3.1 Door Open/closed detection

The CD Module top lid has a contact switch that grounds a signal wire to Butch (ASIC at ref loc U9). At test start, the lid must be closed. If the lid is not closed no further tests may be conducted on the UUT.

<u>Failure Condition</u>	<u>State or error code</u>
Lid switch not connected	UUT held in reset

6.3.2 Data Integrity

The drive is commanded to read a series of tracks on the disc, in various play command formats. The track data are verified algorithmically. Any data errors cause a test failure. Any drive error will cause a test failure.

<u>Failure Condition</u>	<u>State or error code</u>
Drive Error	DSA error condition
Data Err	“failed” message

6.3.3 Audio Playback

The drive is commanded to play an inner audio track, an outer audio track, and intermediate tracks containing intentional errors and defects. The drive must track through these without errors. Any drive error will cause a test failure.

<u>Failure Condition</u>	<u>State or error code</u>
Drive error	DSA error condition

6.3.4 Multiple seek speed test

The drive is commanded to seek between a set of target -times on the disc while a timer is running. The test must complete within the specified time, or the test fails. Any drive error will also cause a test failure.

<u>Failure condition</u>	<u>State or error code</u>
Drive Error	DSA error condition
Excessive time	Seek timeout message

6.3.5 Verify CIRC detection circuit

The area of the test disc with a known defect is played repeatedly while the count of anticipated errors is matched to the actual count. A difference will cause a failure, as will a count of zero. Any unanticipated drive errors will also cause a test failure.

Failure condition

Drive Error
Missed CIRC

State or error code

DSA error condition
MISC pin error message

6.3.6 Subcode R-W Channels

Subcode from the R through W channels is read from a predetermined area of the disc with a known pattern. Any deviation from this pattern causes a failure. Any drive error also causes a failure.

Failure condition

Drive error
R-W subcode error

State or error code

DSA error condition
R-W subcode error

6.3.7 EEPROM read/write

The EEPROM on the CD Module is written with a known pattern, and then read back. Any differences cause a failure.

Failure condition

IC wrong
IC missing or defective

State or error code

System hangs
“failed” message

6.3.8 Subcode Q

Subcodes from the Q channel is read from the disc. If the subcode is not incrementing as it should when the disc plays, the test fails. Any drive error also causes a failure.

Failure condition

Drive Error
Q subcode error

Extended error code

DSA Error Condition
no subcode Q on V4

APPENDIX A

PCBA FUNCTIONAL TEST FIXTURE SPECIFICATION

The bed-of-nails (PCBA) functional test fixture shall incorporate various system components and provide connections from these components to the Unit Under Test (UUT) PCBA.

9VDC power

The UUT connector JP12 shall connect to a 9V DC power source with a DC current meter (**with peak- holding setup required !**) connected in series with the positive side of the DC input power, JP12 pin 2 (TP65). 9VDC power shall be provided to the Jaguar console PCBA by two Atari AC adapters.

108 pin connector

The UUT 108 pin connector shall interface to a Jaguar console PCBA, which will be part of the test fixture and contain the test software. This connection may be provided to the UUT through a CD-ROM extender card to J801.

+5VDC regulator output

The UUT jumper JP224 must be left out and a DC current meter connected in series between JP224 pin 1 (TP9) and JP224 pin 2 (TP337).

+7VDC regulator output

The UUT jumper JP223 must be left out and a peak-holding type DC current meter connected in series between JP223 pin 1 (TP63) and JP223 pin 2 (TP334).

CDM12 motor

The UUT connector JP4 must connect to a CDM12 motor. The CDM12 shall be a permanent part of the test fixture unless the system CDM12 is installed on the UUT PCBA prior to test and shipped as a complete assembly.

CDM12 Laser

The UUT connector JP3 must connect to a CDM12 laser. The CDM12 shall be a permanent part of the test fixture unless the system CDM12 is installed on the UUT PCBA prior to test and shipped as a complete assembly.

BLER

The UUT jumper between pin 1 (TP344) and pin 2 (TP346) of JP225 must be left out. The test fixture must short pin 2 (TP346) and pin 3 (TP343) of JP225. TP 375 (CDV4 signal) should be pulled high to +5V with a 4.7K 1/4W resistor. This enables the test software to measure the block error rate.

JITTER

The Jitter measurement shall be done on the UUT for inner and outer tracks of the CD ROM test disk. Test points TP34 [pin 8 of U8 (HFIN)] and TP345 [pin 12 of U8 (HFGND)] of the UUT shall be used for jitter measurements and corresponding peak to peak voltage measurement. Provision to connect a CD jitter meter (Leader LJM 1851 CD Jitter Meter) at above specified test points shall be provided on the test fixture.

VOLTAGE MEASUREMENTS

The test fixture shall have the capability to measure voltages at the following test points on the UUT.

DC Voltage between TP60 (pin 17 & 18 of U4) and GND (pin 19 of U4)

DC Voltage between TP362 (pin 3 of JP4) and TP363 (pin 4 of JP4)

DC Voltmeters shall be attached to the test fixture to measure the voltages at the above specified test points.

APPENDIX B

STATIC BURN-IN SPECIFICATION

The Static Burn-in facility will include a burn-in chamber operating at a constant temperature of 50 degree C and power distribution network. The power distribution network will provide dual DC supply voltage of 9V and 5V to power the PCBA. The 9V supply will power the PCBA through power jack JP12.

The 5V is supplied to the PCBA through an interconnect pcb (provided by Atari) plugged into connector J801 of the PCBA.

Specification for interconnect PCB.

The interconnect card used in static burn in is a PCB that can be inserted into connector J801 of CD ROM player PCBA (700037) and supplies +5V to PCBA to turn ON the voltage regulators U5 and U13. The interconnect card has no components.

The +5V is at pin 38A and ground is at pin 21A of the adapter card. The 5V can be wired directly to the card from a high capacity power supply . The power supply should be OFF before inserting the card into the PCBA and at the the end of the test the power supply should be turned OFF before removing the card from the PCBA .

